

Volume 22, Number 5

October 2016

# Microscopy AND Microanalysis



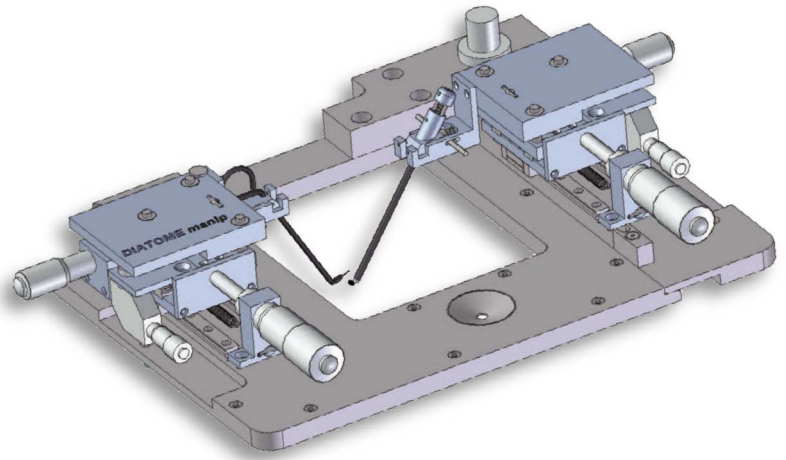
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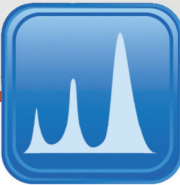
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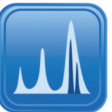
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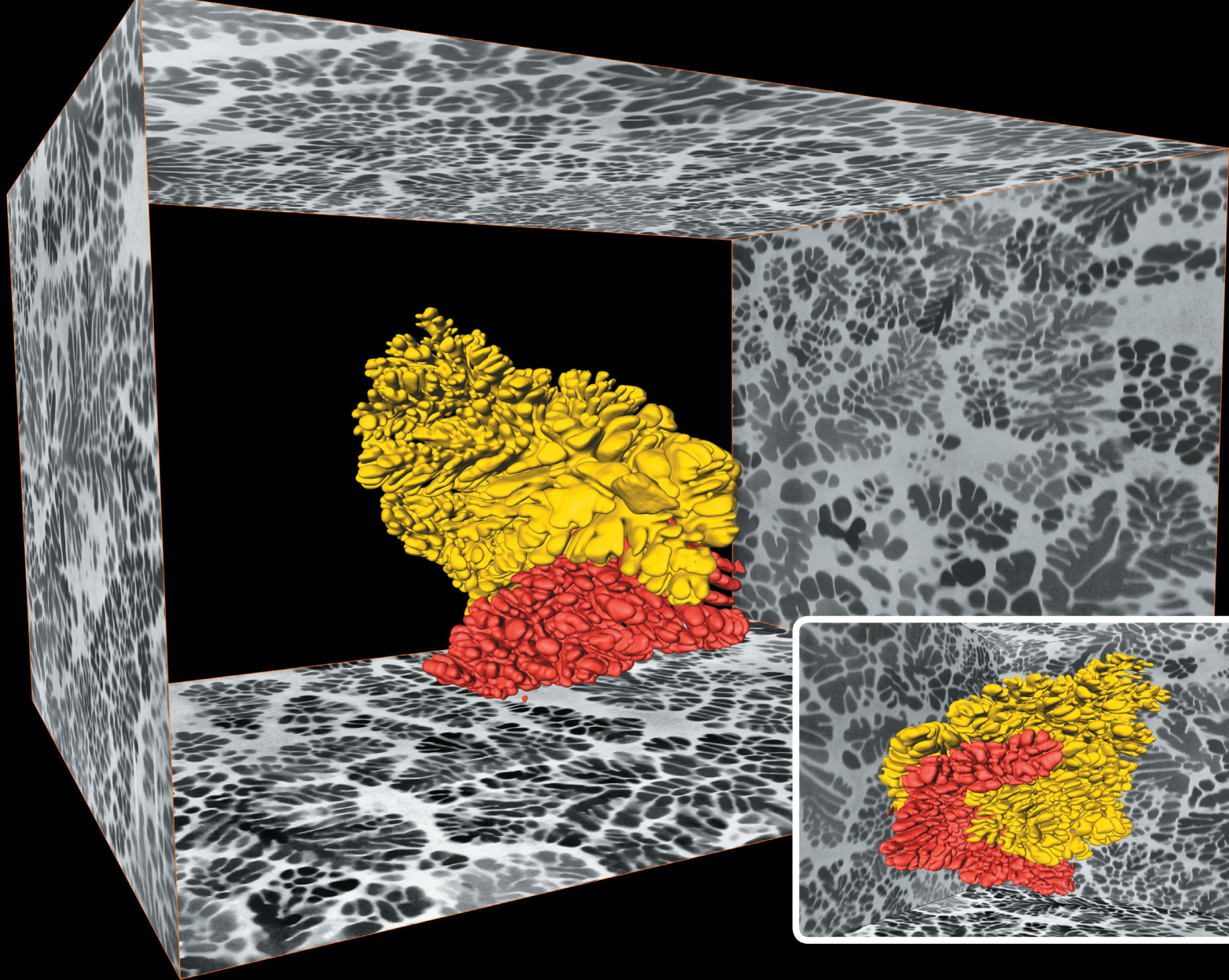
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Volume 22, Number 5  
October 2016

## INSTRUMENTATION AND TECHNIQUES DEVELOPMENT

Novel Polarizing Method for Light Microscopy 933

*Irina G. Palchikova, Evgenii S. Smirnov, and Natalia V. Kamanina*

Removing Beam Current Artifacts in Helium Ion Microscopy: A Comparison of Image Processing Techniques 939

*Anders J. Barlow, Jose F. Portoles, Naoko Sano, and Peter J. Cumpson*

Annular Focused Electron/Ion Beams for Combining High Spatial Resolution with High Probe Current 948

*Anjam Khursheed and Wei Kean Ang*

Thin-Film Phase Plates for Transmission Electron Microscopy Fabricated from Metallic Glasses 955

*Manuel Dries, Simon Hettler, Tina Schulze, Winfried Send, Erich Müller, Reinhard Schneider, Dagmar Gerthsen, Yuansu Luo and Konrad Samwer*

Polyallylamine as an Adhesion Promoter for SU-8 Photoresist 964

*Shiladitya Chatterjee, George H. Major, Barry M. Lunt, Massoud Kaykhahi and Matthew R. Linford*

Why Do We Need to Use Three-Dimensional (3D) Fourier Transform (FT) Analysis to Evaluate a High-Performance Transmission Electron Microscope (TEM)? 971

*Kazuo Ishizuka and Koji Kimoto*

Decontamination in the Electron Probe Microanalysis with a Peltier-Cooled Cold Finger 981

*Ben Buse, Stuart Kearns, Charles Clapham and Donovan Hawley*

## MATERIALS APPLICATIONS

Identification of Nanocrystalline Inclusions in the Bismuth-Doped Silica Fibers and Preforms 987

*Liudmila D. Iskhakova, Filipp O. Milovich, Valery M. Mashinsky, Alexander S. Zlenko, Sergey E. Borisovsky and Evgeny M. Dianov*

Characterization of Amorphous Oxide Nano-Thick Layers on 316L Stainless Steel by Electron Channeling Contrast Imaging and Electron Backscatter Diffraction 997

*Mahrokh Dorri, Stéphane Turgeon, Nicolas Brodusch, Maxime Cloutier, Pascale Chevallier, Raynald Gauvin and Diego Mantovani*

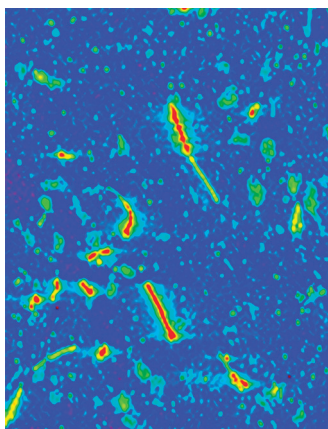
On the Chemical Signature and Origin of Diccoppertrihydroxycarbonate ( $\text{Cu}_2(\text{OH})_3\text{HCO}_3$ ) Formed on Copper Miniatures of 17th and 18th Centuries 1007

*Alfredina Veiga, Dora Martins Teixeira, António J. Candeias, José Mirão, Paulo Simões Rodrigues and Jorge Ginja Teixeira*

## BIOLOGICAL APPLICATIONS

Cytotoxicity of Experimental Resin Composites on Mesenchymal Stem Cells Isolated from Two Oral Sources 1018

*Alexandra Roman, Emöke Páll, Mărioara Moldovan, Darian Rusu, Olga Şorîţău, Dana Feştilă and Mihaela Lupş*



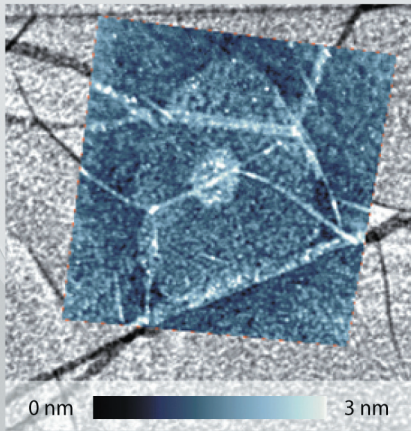
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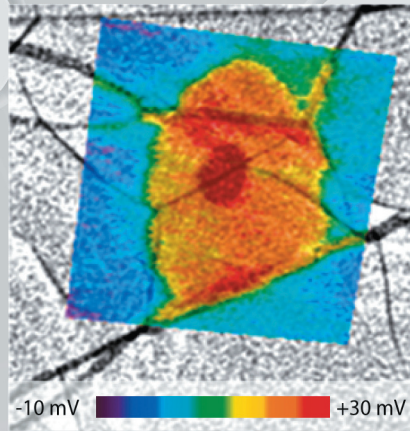
## Contents continued

- Zinc-Containing Restorations Create Amorphous Biogenic Apatite at the Carious Dentin Interface: A X-Ray Diffraction (XRD) Crystal Lattice Analysis 1034  
*Manuel Toledano, Fátima S. Aguilera, Modesto T. López-López, Estrella Osorio, Manuel Toledano-Osorio and Raquel Osorio*
- Aberration-Corrected Transmission Electron Microscopic Study of the Central Dark Line Defect in Human Tooth Enamel Crystals 1047  
*José Reyes-Gasga, Joseph Hémmérlé and Etienne F. Brès*
- Electron Microscopy Findings in *N*-Methyl-*N*-Nitrosourea-Induced Mammary Tumors 1056  
*Ana I. Faustino-Rocha, Ana M. Calado, Adelina Gama, Rita Ferreira, Mário Ginja and Paula A. Oliveira*
- Focused X-Ray Histological Analyses to Reveal Asbestos Fibers and Bodies in Lungs and Pleura of Asbestos Exposed Subjects 1062  
*Lorella Pascolo, Alessandra Gianoncelli, Clara Rizzardi, Martin de Jonge, Daryl Howard, David Paterson, Francesca Cammisuli, Murielle Salomé, Paolo De Paoli, Mauro Melato and Vincenzo Canzonieri*
- Polarization Second Harmonic Generation Discriminates Between Fresh and Aged Starch-Based Adhesives Used in Cultural Heritage 1072  
*Sotiris Psilodimitrakopoulos, Evaggelia Gavgiotaki, Kristallia Melessanaki, Vassilis Tsafas and George Filippidis*
- Spectroscopic and Microscopic Study of Peroxyformic Pulping of Agave Waste 1084  
*Hilda M. Hernández-Hernández, Jorge J. Chanona-Pérez, Alberto Vega, Pablo Ligeró, Reynold R. Farrera-Rebollo, Jorge A. Mendoza-Pérez, Georgina Calderón-Domínguez and Norma Güemes Vera*
- Diplopods as Soil Bioindicators of Toxicity After Application of Residues From Sewage Treatment Plants and Ethanol Industry 1098  
*Cintya A. Christofolletti, Annelise Francisco, Janáína Pedro-Escher, Vinicius D. Gastaldi and Carmem S. Fontanetti*
- BOOK REVIEW**
- Correlative Light and Electron Microscopy II 1111  
*Nadine Soplop*

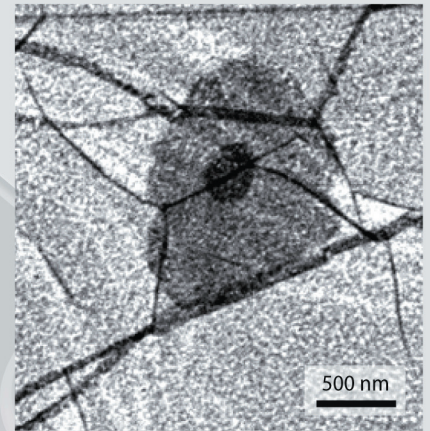
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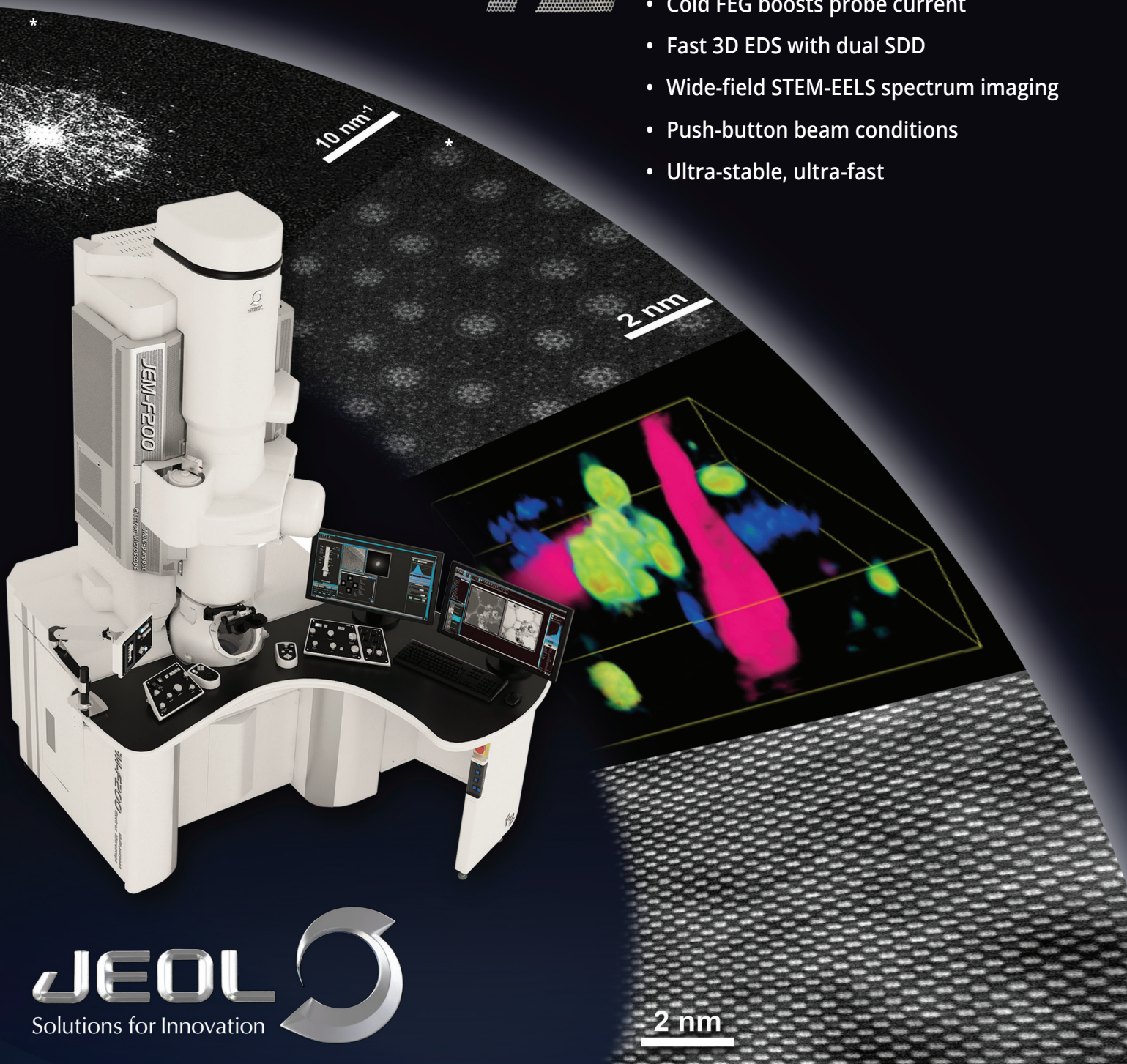
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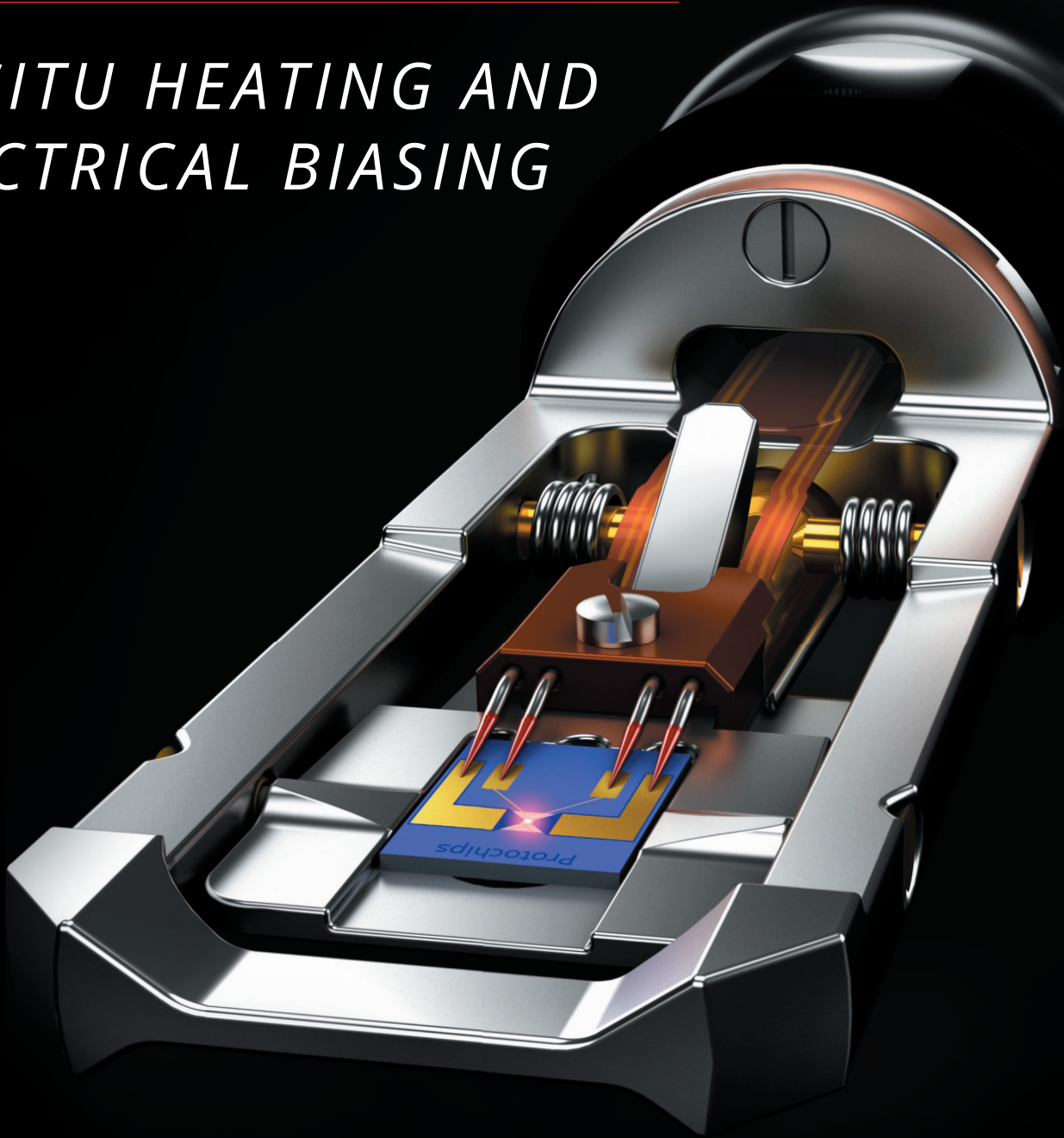
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